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-	342	((fault adj (test\$3 or simulat\$4)) and (test near4 (vector\$1 or pattern\$1 or sequence\$1 or list\$1)) and (((power adj suppl\$3) near4 current\$1) near\$3 (transient\$2 or spike\$1 or surge\$1)))	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2003/10/28 17:59
-	259	((fault adj (test\$3 or simulat\$4)) and (test near4 (vector\$1 or pattern\$1 or sequence\$1 or list\$1)) and (((power adj suppl\$3) near4 current\$1) near\$3 (transient\$2 or spike\$1 or surge\$1))) and @ad<20000124	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2003/10/28 17:59
-	57	(((((fault adj (test\$3 or simulat\$4)) and (test near4 (vector\$1 or pattern\$1 or sequence\$1 or list\$1)) and (((power adj suppl\$3) near4 current\$1) near\$3 (transient\$2 or spike\$1 or surge\$1)))) and @ad<20000124) and (logic adj signal\$1)	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2003/10/28 17:59
-	1	(((((fault adj (test\$3 or simulat\$4)) and (test near4 (vector\$1 or pattern\$1 or sequence\$1 or list\$1)) and (((power adj suppl\$3) near4 current\$1) near\$3 (transient\$2 or spike\$1 or surge\$1)))) and @ad<20000124) and (logic adj signal\$1) and (((power adj suppl\$3) near4 current\$1) near\$3 (transient\$2 or spike\$1 or surge\$1)))	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2003/10/28 17:58
-	7	(((((fault adj (test\$3 or simulat\$4)) and (test near4 (vector\$1 or pattern\$1 or sequence\$1 or list\$1)) and (((power adj suppl\$3) near4 current\$1) near\$3 (transient\$2 or spike\$1 or surge\$1)))) and @ad<20000124) and (logic adj signal\$1) and (((power adj suppl\$3) same current\$1) same (transient\$2 or spike\$1 or surge\$1)))	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2003/10/28 17:59
-	36	((fault adj (test\$3 or simulat\$4)) and (test near4 (vector\$1 or pattern\$1 or sequence\$1 or list\$1)) and (((power adj suppl\$3) same current\$1) same (transient\$2 or spike\$1 or surge\$1)))	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2003/10/28 17:59
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1 A novel wavelet transform based transient current analysis for fault detection and localization*Bhunia, S.; Roy, K.; Segura, J.;*

Design Automation Conference, 2002. Proceedings. 39th , 10-14

June 2002

Page(s): 361 -366

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Wanli Jiang , Bapiraju Vinnakota

Proceedings of the 36th ACM/IEEE conference on Design automation conference June 1999

2 [Contest: a concurrent test generator for sequential circuits](#)

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Vishwani D. Agrawal , Kwang-Ting Cheng , Prathima Agrawal

Proceedings of the 25th ACM/IEEE conference on Design automation June 1988

This paper describes the application of a concurrent fault simulator to automatic test vector generation. As faults are simulated in the fault simulator a cost function is simultaneously computed. A simple cost function is the distance (in terms of the number of gates and flip-flops) of a fault effect from a primary output. The input vector is then modified to reduce the cost function until a test is found. The paper presents experimental results showing the effectiveness of this method in ...

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 Dirk Niggemeyer, Elizabeth M. Rudnick


ACM Transactions on Design Automation of Electronic Systems (TODAES) October 2003

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Systems-on-Chips often contain a large amount of embedded memory. In order to obtain sufficiently high yield, efficient diagnosis and repair facilities are needed for the memories. A novel and efficient approach for collecting complete failure data during on-chip memory testing is proposed that can be combined with a row/column reconfiguration algorithm for complete on-chip memory repair. A sequence of diagnostic tests of linear order is utilized that detects and localizes all cells involved in ...

2 [A circuit level fault model for resistive bridges](#)

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 Zhuo Li, Xiang Lu, Wangqi Qiu, Weiping Shi, D. M. H. Walker

ACM Transactions on Design Automation of Electronic Systems (TODAES) October 2003

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Delay faults are an increasingly important test challenge. Modeling bridge faults as delay faults helps delay tests to detect more bridge faults. Traditional bridge fault models are incomplete because these models only model the logic faults or these models are not efficient to use in delay tests for large circuits. In this article, we propose a physically realistic yet economical resistive bridge fault model to model delay faults as well as logic faults. An accurate yet simple delay calculation ...

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Graham F. Forsyth , Michael E. Larkin , Glen A. Wallace

Proceedings of the third international conference on Industrial and engineering applications of artificial intelligence and expert systems - Volume 2 June 1990

An approach to verify the knowledge base of a diagnostic expert system is described. An heuristic knowledge base collected from domain experts by interviews was analysed and the reasons for changes between versions were noted. The knowledge base was then compared with a small causal qualitative model of the device covered by the heuristic knowledge. Conclusions are drawn regarding the quality of the heuristic knowledge and indicate how it is planned to use the comparison of heuristic and ca ...

2 [Knowledge based fault management for OSI networks](#) 100%

Celia A. Joseph , A. Sherzer , K. Muralidhar

Proceedings of the third international conference on Industrial and engineering applications of artificial intelligence and expert systems - Volume 1 June 1990

The OSI Fault Management system (OSIFaM) is an evolving knowledge-based system for fault management of Open System Interconnection (OSI) networks. Our goal is to develop a knowledge-based tool that will reduce the expertise needed to recognize, diagnose and correct faults in OSI networks. For our first implementation, we are focusing on MAP 3.0 networks. This paper provides an overview of fault management in general, a brief survey of other fault management developments, the characteristics ...

3 [A data acquisition methodology for on-chip repair of embedded memories](#) 100%

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1 An approach to dynamic power consumption current testing of CMOS ICs

Segura, J.A.; Roca, M.; Mateo, D.; Rubio, A.;

VLSI Test Symposium, 1995. Proceedings., 13th IEEE , 30 April-3 May 1995

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2 GOS defects in SRAM: fault modeling and testing possibilities

Segura, J.A.; Rubio, A.;

Memory Technology, Design and Testing, 1994., Records of the IEEE International Workshop on , 8-9 Aug. 1994

Page(s): 66 -71

[\[Abstract\]](#) [\[PDF Full-Text \(376 KB\)\]](#) **IEEE CNF**

3 CURRENT VS. LOGIC TESTING OF GATE OXIDE SHORT, FLOATING GATE AND BRIDGING FAILURES IN CMOS

Rodriguez-Montanes, R.; Segura, J.A.; Champac, V.H.; Figueras, J.; Rubio, J.A.;

Test Conference, 1991, Proceedings., International , 26-30 Oct 1991
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1 New atpg algorithm for iddt-based testing

Chehab, A.; Makki, R.; Maddali, R.;

Microelectronics, The 14th International Conference on 2002 - ICM ,
Dec. 11-13, 2002

Page(s): 224 -227

[\[Abstract\]](#) [\[PDF Full-Text \(237 KB\)\]](#) **IEEE CNF**

2 I_{DDT} testing of embedded CMOS SRAMs

Kumar, S.A.; Makki, R.Z.; Binkley, D.M.;

Design, Automation and Test in Europe Conference and Exhibition,
2002. Proceedings , 4-8 March 2002

Page(s): 1117

[\[Abstract\]](#) [\[PDF Full-Text \(213 KB\)\]](#) **IEEE CNF**

3 i_{DDT} test methodologies for very deep sub-micron CMOS circuits

Chehab, A.; Makki, R.; Spica, M.; Wu, D.;

Electronic Design, Test and Applications, 2002. Proceedings. The
First IEEE International Workshop on , 29-31 Jan. 2002

Page(s): 403 -407

[\[Abstract\]](#) [\[PDF Full-Text \(375 KB\)\]](#) **IEEE CNF**

4 SRAM test using on-chip dynamic power supply current sensor

Jian Liu; Makki, R.Z.;

Memory Technology, Design and Testing, 1998. Proceedings.
International Workshop on , 24-25 Aug. 1998

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[\[Abstract\]](#) [\[PDF Full-Text \(56 KB\)\]](#) **IEEE CNF**

5 Testing Embedded Memories: Is Bist The Ultimate Solution? Testing Of Embedded Memories-the Aggregate

Makki, R.Z.;

Test Symposium, 1998. ATS '98. Proceedings. Seventh Asian , 2-4 Dec. 1998
Page(s): 519 -519

[\[Abstract\]](#) [\[PDF Full-Text \(96 KB\)\]](#) [IEEE CNF](#)

6 Dynamic power supply current testing of CMOS SRAMs

Jian Liu; Makki, R.Z.; Kayssi, A.;

Test Symposium, 1998. ATS '98. Proceedings. Seventh Asian , 2-4 Dec. 1998
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7 A high level language implementation of a general purpose telemetry system for biomedical applications

Rorie, J.F.; Simmerman, J.K.; Makki, R.Z.; Piendl, R.D.;

System Theory, 1996., Proceedings of the Twenty-Eighth Southeastern Symposium on , 31 March-2 April 1996
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8 Transient power supply current testing of digital CMOS circuits

Makki, R.Z.; Shyang-Tai Su; Nagle, T.;

Test Conference, 1995. Proceedings., International , 21-25 Oct. 1995
Page(s): 892 -901

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9 Power supply current detectability of SRAM defects

Jian Liu; Makki, R.;

Test Symposium, 1995., Proceedings of the Fourth Asian , 23-24 Nov. 1995
Page(s): 367 -373

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10 Dynamic power supply current monitoring of SRAMs

Shyang-Tai Su; Makki, R.Z.; Nagle, H.T.; Jian Liu;

ASIC Conference and Exhibit, 1994. Proceedings., Seventh Annual IEEE International , 19-23 Sept. 1994
Page(s): 370 -373

[\[Abstract\]](#) [\[PDF Full-Text \(336 KB\)\]](#) [IEEE CNF](#)

11 A testable static RAM structure f r efficient c verage f

pattern sensitive faults*Shyang-Tai Su; Makki, R.Z.;*

VLSI Test Symposium, 1992. '10th Anniversary. Design, Test and Application: ASICs and Systems-on-a-Chip', Digest of Papers., 1992
IEEE , 7-9 April 1992

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[\[Abstract\]](#) [\[PDF Full-Text \(360 KB\)\]](#) **IEEE CNF**

12 ON THE INTEGRATION OF DESIGN AND MANUFACTURING FOR IMPROVED TESTABILITY*Makki, R.Z.; Daneshvar, K.; Tranjan, F.; Greene, R.;*

Test Conference, 1991, Proceedings., International , 26-30 Oct 1991

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[\[Abstract\]](#) [\[PDF Full-Text \(488 KB\)\]](#) **IEEE CNF**

13 On controllability estimation to aid in partitioning logic circuits*Sern, J.; Makki, R.;*

Southeastcon '91., IEEE Proceedings of , 7-10 April 1991

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14 NEPTUNE: an automatic test pattern generator for finite state machines*Divekar, S.; Makki, R.Z.; Mostafavi, T.M.;*

Southeastcon '91., IEEE Proceedings of , 7-10 April 1991

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15 A VLSI based logic analyzer interface for a microprocessor development system*Lee, B.H.; Makki, R.Z.; Rohe, C.;*

System Theory, 1991. Proceedings., Twenty-Third Southeastern Symposium on , 10-12 March 1991

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Ramamurthy, H.; Karandikar, A.; Verma, R.;
Communication Systems, 2002. ICCS 2002. The 8th International
Conference on , Volume: 2 , 25-28 Nov. 2002
Page(s): 938 -942 vol.2

[\[Abstract\]](#) [\[PDF Full-Text \(430 KB\)\]](#) **IEEE CNF**

2 I_{DD} pulse response testing on analog and digital CMOS circuits

Beasley, J.S.; Ramamurthy, H.; Ramirez-Angulo, J.; DeYong, M.;
Test Conference, 1993. Proceedings., International , 17-21 Oct. 1993

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3 i_{DD} pulse response testing: a unified approach to testing digital and analogue ICs

Beasley, J.; Ramamurthy, H.; Ramirez-Angulo, J.; Deyong, M.;
Electronics Letters , Volume: 29 Issue: 24 , 25 Nov. 1993

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Testing Mixed Signal Circuits and Systems (Ref. No: 1997/361), IEE Colloquium on , 23 Oct. 1997

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Power Electronics and Applications, 1993., Fifth European Conference on , 13-16 Sep 1993

Page(s): 191 -196 vol.8

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Power Electronics Specialist, 2003. PESC '03. IEEE 34th Annual Conference on , Volume: 2 , 15-19 June 2003

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[\[Abstract\]](#) [\[PDF Full-Text \(471 KB\)\]](#) **IEEE CNF**

4 CMOS IC stuck- pen-fault electrical effects and design considerations

Soden, J.M.; Treece, R.K.; Taylor, M.R.; Hawkins, C.F.;
Test Conference, 1989. Proceedings. 'Meeting the Tests of Time',
International , 29-31 Aug. 1989
Page(s): 423 -430

[\[Abstract\]](#) [\[PDF Full-Text \(624 KB\)\]](#) **IEEE CNF**

5 Performance analysis and signal processing in a current sensing power MOSFET (SENSEFET)

Yuvarajan, S.; Wang, L.;
Industry Applications Society Annual Meeting, 1991., Conference
Record of the 1991 IEEE , 28 Sept.-4 Oct. 1991
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6 A novel high efficiency UPS using improved inverter and DC to DC converter

Eishima, Y.; Jinno, M.; Tominaga, F.; Sakamoto, H.; Harada, K.;
Telecommunications Energy Conference, 1991. INTELEC '91., 13th
International , 5-8 Nov. 1991
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[\[Abstract\]](#) [\[PDF Full-Text \(320 KB\)\]](#) **IEEE CNF**

7 Design and testing of power supplies for the high power gyrotron

Tsuneoka, M.; Fujita, H.; Nagashima, T.; Cho, Y.; Yamane, T.;
Hayakawa, S.; Ohtsuka, S.; Harada, K.; Yoshida, T.; Shibuya, T.;
Ishibashi, M.;
Fusion Engineering, 1991. Proceedings., 14th IEEE/NPSS Symposium
on , 30 Sept.-3 Oct. 1991
Page(s): 497 -500 vol.1

[\[Abstract\]](#) [\[PDF Full-Text \(260 KB\)\]](#) **IEEE CNF**

8 Groundbounce in ASIC's: model and test results

Diaz-Olavarrieta, L.;
Electromagnetic Compatibility, 1991. Symposium Record. IEEE 1991
International Symposium on , 12-16 Aug. 1991
Page(s): 387 -392

[\[Abstract\]](#) [\[PDF Full-Text \(576 KB\)\]](#) **IEEE CNF**

9 Test generation and fault detection techniques in mixed circuits

Bracho, S.; Martinez, M.; Arguelles, J.;

Circuits and Systems, 1992., Proceedings of the 35th Midwest Symposium on , 9-12 Aug. 1992

Page(s): 931 -937 vol.2

[\[Abstract\]](#) [\[PDF Full-Text \(440 KB\)\]](#) **IEEE CNF**

10 Design of an electric power interface compatibility 200 kVa mobile test facility

Williams, S.; Sityar, I.; Rager, P.; Reitweisner, J.;

Industry Applications Society Annual Meeting, 1992., Conference Record of the 1992 IEEE , 4-9 Oct. 1992

Page(s): 1322 -1326 vol.2

[\[Abstract\]](#) [\[PDF Full-Text \(320 KB\)\]](#) **IEEE CNF**

11 Management of high current transients in the CWDD injector 200 kV power system

Carwardine, J.A.; Pile, G.; Zinneman, T.E.;

Particle Accelerator Conference, 1993., Proceedings of the 1993 , 17-20 May 1993

Page(s): 3210 -3212 vol.4

[\[Abstract\]](#) [\[PDF Full-Text \(240 KB\)\]](#) **IEEE CNF**

12 A high power water cooled resistor for the high voltage power supply in the TRIUMF RF system

Jensen, K.; Blaker, G.; Kuramoto, R.;

Particle Accelerator Conference, 1993., Proceedings of the 1993 , 17-20 May 1993

Page(s): 1300 -1302 vol.2

[\[Abstract\]](#) [\[PDF Full-Text \(260 KB\)\]](#) **IEEE CNF**

13 Filament power supply improvement of the TRIUMF RF system

Mitra, A.K.; Lu, J.J.;

Particle Accelerator Conference, 1993., Proceedings of the 1993 , 17-20 May 1993

Page(s): 1303 -1305 vol.2

[\[Abstract\]](#) [\[PDF Full-Text \(212 KB\)\]](#) **IEEE CNF**

14 I_{DD} pulse response testing in analog and digital CMOS circuits

Beasley, J.S.; Ramamurthy, H.; Ramirez-Angulo, J.; DeYong, M.;

Test Conference, 1993. Proceedings., International , 17-21 Oct. 1993

Page(s): 626 -634

[\[Abstract\]](#) [\[PDF Full-Text \(480 KB\)\]](#) **IEEE CNF**

15 Modeling the effect of ground bounce on noise margin

Haydt, M.S.; Owens, R.; Mourad, S.;

Test Conference, 1994. Proceedings., International , 2-6 Oct. 1994

Page(s): 279 -285

[\[Abstract\]](#) [\[PDF Full-Text \(420 KB\)\]](#) **IEEE CNF**

16 An off-chip $IDDq$ current measurement unit for telecommunication ASICs

Manhaeve, H.A.R.; Wrighton, P.L.; van Sas, J.; Swerts, U.;

Test Conference, 1994. Proceedings., International , 2-6 Oct. 1994

Page(s): 203 -212

[\[Abstract\]](#) [\[PDF Full-Text \(784 KB\)\]](#) **IEEE CNF**

17 A new parallel processing UPS with the performance of harmonic suppression and reactive power compensation

Hurng-Liahng Jou; Jinn-Chang Wu;

Power Electronics Specialists Conference, PESC '94 Record., 25th Annual IEEE , 20-25 June 1994

Page(s): 1443 -1450 vol.2

[\[Abstract\]](#) [\[PDF Full-Text \(540 KB\)\]](#) **IEEE CNF**

18 Dynamic power supply current monitoring of SRAMs

Shyang-Tai Su; Makki, R.Z.; Nagle, H.T.; Jian Liu;

ASIC Conference and Exhibit, 1994. Proceedings., Seventh Annual IEEE International , 19-23 Sept. 1994

Page(s): 370 -373

[\[Abstract\]](#) [\[PDF Full-Text \(336 KB\)\]](#) **IEEE CNF**

19 Fuzzy logic protection circuit provides a flexible response in severe transient environments

Grill, T.F.; Roy, B.P.; Worden, J.A.;

WESCON/94. 'Idea/Microelectronics'. Conference Record , 27-29
Sept. 1994
Page(s): 103 -109

[\[Abstract\]](#) [\[PDF Full-Text \(524 KB\)\]](#) **IEEE CNF**

20 Interface specifications for a global grounding topology
Ashdown, B.; Korbel, N.; Panesar, B.;
Telecommunications Energy Conference, 1994. INTELEC '94., 16th
International , 30 Oct.-3 Nov. 1994
Page(s): 400 -406

[\[Abstract\]](#) [\[PDF Full-Text \(456 KB\)\]](#) **IEEE CNF**

21 Transient power supply current testing of digital CMOS circuits
Makki, R.Z.; Shyang-Tai Su; Nagle, T.;
Test Conference, 1995. Proceedings., International , 21-25 Oct. 1995

Page(s): 892 -901

[\[Abstract\]](#) [\[PDF Full-Text \(864 KB\)\]](#) **IEEE CNF**

22 An approach to dynamic power consumption current testing of CMOS ICs
Segura, J.A.; Roca, M.; Mateo, D.; Rubio, A.;
VLSI Test Symposium, 1995. Proceedings., 13th IEEE , 30 April-3
May 1995
Page(s): 95 -100

[\[Abstract\]](#) [\[PDF Full-Text \(432 KB\)\]](#) **IEEE CNF**

23 Current test methods in mixed signal circuits
Bracho, S.; Martinez, M.; Arguelles, J.;
Circuits and Systems, 1995., Proceedings., Proceedings of the 38th
Midwest Symposium on , Volume: 2 , 13-16 Aug. 1995
Page(s): 1162 -1167 vol.2

[\[Abstract\]](#) [\[PDF Full-Text \(524 KB\)\]](#) **IEEE CNF**

24 An i_{DD} transient analysis technique for defect detection in digital integrated circuits
Beasley, J.; Ramirez-Angulo, J.; Steiner, R.;
Circuits and Systems, 1995., Proceedings., Proceedings of the 38th

Midwest Symposium on , Volume: 1 , 13-16 Aug. 1995

Page(s): 286 -289 vol.1

[\[Abstract\]](#) [\[PDF Full-Text \(280 KB\)\]](#) **IEEE CNF**

25 Power supply current detectability of SRAM defects

Jian Liu; Makki, R.;

Test Symposium, 1995., Proceedings of the Fourth Asian , 23-24

Nov. 1995

Page(s): 367 -373

[\[Abstract\]](#) [\[PDF Full-Text \(496 KB\)\]](#) **IEEE CNF**

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1 Defect detection using power supply transient signal analysis

Germida, A.; Zheng Yan; Plusquellic, J.F.; Muradali, F.;
Test Conference, 1999. Proceedings. International , 28-30 Sept. 1999
Page(s): 67 -76

[\[Abstract\]](#) [\[PDF Full-Text \(916 KB\)\]](#) **IEEE CNF**

2 8-bit multiplier simulation experiments investigating the use of power supply transient signals for the detection of CMOS defects

Plusquellic, J.F.; Germida, A.; Yan, Z.;
Defect and Fault Tolerance in VLSI Systems, 1999. DFT '99. International Symposium on , 1-3 Nov. 1999
Page(s): 68 -76

[\[Abstract\]](#) [\[PDF Full-Text \(160 KB\)\]](#) **IEEE CNF**

3 Time- and frequency-domain transient signal analysis for defect detection in CMOS digital ICs

Plusquellic, J.F.; Chiarulli, D.M.; Levitan, S.P.;
Circuits and Systems I: Fundamental Theory and Applications, IEEE Transactions on , Volume: 46 Issue: 11 , Nov. 1999
Page(s): 1390 -1394

[\[Abstract\]](#) [\[PDF Full-Text \(152 KB\)\]](#) **IEEE JNL**

4 An automated technique to identify defective CMOS devices based on linear regression analysis of transient signal data

Plusquellic, J.F.; Chiarulli, D.M.; Levitan, S.P.;
IDDQ Testing, 1998. Proceedings. 1998 IEEE International Workshop on , November 12-13, 1998
Page(s): 32 -36

[\[Abstract\]](#) [\[PDF Full-Text \(152 KB\)\]](#) **IEEE CNF**

5 Identification of defective CMOS devices using correlation and regression analysis of frequency domain transient signal data

Plusquellic, J.F.; Chiarulli, D.M.; Levitan, S.P.;

Test Conference, 1997. Proceedings., International , 1-6 Nov. 1997

Page(s): 40 -49

[\[Abstract\]](#) [\[PDF Full-Text \(1112 KB\)\]](#) **IEEE CNF**

6 Digital integrated circuit testing using transient signal analysis

Plusquellic, J.F.; Chiarulli, D.M.; Levitan, S.P.;

Test Conference, 1996. Proceedings., International , 20-25 Oct. 1996

Page(s): 481 -490

[\[Abstract\]](#) [\[PDF Full-Text \(1024 KB\)\]](#) **IEEE CNF**

7 Digital IC device testing by transient signal analysis (TSA)

Plusquellic, J.F.; Chiarulli, D.M.; Levitan, S.P.;

Electronics Letters , Volume: 31 Issue: 18 , 31 Aug. 1995

Page(s): 1568 -1570

[\[Abstract\]](#) [\[PDF Full-Text \(276 KB\)\]](#) **IEE JNL**

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